

## ARTICLE

# Growth and Electronic Properties of Ag Nanoparticles on Reduced CeO<sub>2-x</sub>(111) Films

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Ag nanoparticles grown on reduced CeO<sub>2-x</sub> thin films have been studied by X-ray photoelectron spectroscopy and resonant photoelectron spectroscopy of the valence band to understand the effect of oxygen vacancies in the CeO<sub>2-x</sub> thin films on the growth and interfacial electronic properties of Ag. Ag grows as three-dimensional particles on the CeO<sub>2-x</sub>(111) surface at 300 K. Compared to the fully oxidized ceria substrate surface, Ag favors the growth of smaller particles with a larger particle density on the reduced ceria substrate surface, which can be attributed to the nucleation of Ag on oxygen vacancies. The binding energy of Ag3d increases when the Ag particle size decreases, which is mainly attributed to the final-state screening. The interfacial interaction between Ag and CeO<sub>2-x</sub>(111) is weak. The resonant enhancement of the 4f level of Ce<sup>3+</sup> species in RPES indicates a partial Ce<sup>4+</sup>→Ce<sup>3+</sup> reduction after Ag deposited on reduced ceria surface. The sintering temperature of Ag on CeO<sub>1.85</sub>(111) surface during annealing is a little higher than that of Ag on CeO<sub>2</sub>(111) surface, indicating that Ag nanoparticles are more stable on the reduced ceria surface.

**Key words:** Silver, Ceria, Growth, Electronic structure, X-ray photoelectron spectroscopy, Resonant photoelectron spectroscopy

## I. INTRODUCTION

In heterogeneous catalysis, Ag-on-ceria systems have been widely used in a variety of catalytic reactions, such as in NO reduction, CO and hydrocarbon oxidation [1, 2], methane oxidation [3], and formaldehyde oxidative decomposition [4]. Moreover, the use of Ag deposited on ceria was also found to increase the rate of carbon gasification in the oxidation of carbon soot particles compared to other noble metals [5–7]. To gain fundamental insight into the nature of chemistry of Ag/ceria catalysts, several surface science studies in terms of the growth, structure, and reactivity of vapor-deposited Ag nanoparticles on CeO<sub>2-x</sub>(111)(0<x<5) surfaces have been performed [8–10]. Recently, we studied the growth and interfacial electronic properties of Ag on the CeO<sub>2</sub>(111) thin films using synchrotron radiation photoemission spectroscopy [8]. A three-dimensional (3D) growth mode with a density of ~1×10<sup>12</sup> particles/cm<sup>2</sup> for Ag on a well-ordered CeO<sub>2</sub>(111) was reported. However, when the CeO<sub>2</sub>(111) surface has a high density of defects (*i.e.*, less-ordered), an initial two-dimensional (2D) growth up to 0.3 ML due to Ag population on defect sites followed by a 3D growth with a density of ~4×10<sup>12</sup> particles/cm<sup>2</sup> for Ag was observed. Farmer *et*

*al.* also reported that Ag binds more strongly on the more reduced CeO<sub>2-x</sub>(111) surfaces using microcalorimetric techniques [9], which is also consistent with the scanning tunneling microscopy (STM) studies of Ag nanoparticles grown on ceria [10], which showed surface oxygen vacancies act as nucleation centers for Ag nanoparticles.

In this work, we focus the effect of surface oxygen vacancies in the ceria films on the growth of Ag particles and the Ag-ceria interfacial electronic properties. We use resonant photoelectron spectroscopy (RPES) together with X-ray photoelectron spectroscopy (XPS) and low energy electron diffraction (LEED) to investigate the growth, nucleation, and electronic properties of Ag on the reduced CeO<sub>2-x</sub>(111) thin films which were prepared *in situ* on a Ru(0001) substrate. Resonant photoemission using synchrotron radiation is one of the most sensitive tools for the detection of changes in the oxidation state of ceria [11, 12]. This method is based on determining Ce4f occupancy in the valence band spectra in the Ce4d→4f photoabsorption region [12]. Different 4f configurations for Ce<sup>4+</sup>(4f<sup>0</sup>) and Ce<sup>3+</sup>(4f<sup>1</sup>) result in different spectroscopic features in the valence-band (VB) spectra [13]. From the core-level binding energies and Auger parameters, the electronic properties of the Ag/CeO<sub>2</sub> interface with various sizes of Ag nanoparticles are determined. The thermal stability/sintering process of the Ag nanoparticles with different initial sizes at elevated temperatures is also ex-

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amined.

## II. EXPERIMENTS

All the experiments were performed at the Photoemission Endstation at beamline U20 in the National Synchrotron Radiation Laboratory, Hefei, China. The detailed description of the beamline and endstation can be found in our previous work [8]. Briefly, this beamline is connected to a bending magnet and equipped with three gratings that cover photon energies from 60 eV to 1000 eV with a resolving power ( $E/\Delta E$ ) better than 1000. The endstation consists of an analysis chamber and a sample preparation chamber, whose base pressures are 26.7 and 66.7 nPa, respectively, and a sample load-lock system. The analysis chamber is equipped with a VG Scienta R3000 electron energy analyzer, a twin anode (Mg and Al) X-ray source, rear-view LEED optics, a quadrupole mass spectrometer (Pfeiffer QMS220), and an Ar<sup>+</sup> sputter gun. The preparation chamber is connected with a quick load-lock port and houses an e-beam evaporator for Ce and a home-built evaporator for Ag.

The photoemission spectra were recorded at normal emission and have been normalized to the photon flux which was calibrated by measuring the Au4f spectra from a clean Au foil attached to the sample holder. Valence band spectra were recorded with a photon energy of 170 eV. Al K $\alpha$  (1486.6 eV) was used to probe Ag3d and O1s core levels. All the binding energies (BEs) were calibrated with respect to the Au4f<sub>7/2</sub> (BE=84 eV) feature from the Au foil, which was measured immediately after each spectrum.

The Ru(0001) single crystal (10 mm diameter and 2 mm thickness) sample, purchased from MaTeck GmbH, Germany, was used as the substrate. The sample was mounted on a Mo sample holder which was fixed by Ta wires at the sides. A K-type thermocouple was used to monitor the sample temperature. The sample was cleaned by repeated cycles of Ar<sup>+</sup> bombardment at room temperature followed by annealing up to 1300 K until no contaminants were detected by XPS and a sharp LEED pattern was observed.

Reduced CeO<sub>2-x</sub>(111) thin films were prepared by evaporating cerium metal onto Ru(0001) with a constant substrate temperature of 700 K in the presence of oxygen gas followed by annealing at 980 K for 10 min [14–16]. Our previous studies have shown that the fully oxidized CeO<sub>2</sub> grew with an oxygen pressure of 26.6  $\mu$ Pa and a Ce flux of 0.003 nm/min [8]. The reduced ceria can be obtained by decreasing the oxygen pressure during the cerium evaporation. By varying the oxygen pressure, different degree of reduced ceria films can be obtained. For example, oxygen pressure of 8  $\mu$ Pa was used to obtain CeO<sub>1.81</sub> thin films. Metallic cerium (99.99%, Goodfellow) evaporated from an electron bombarded W crucible using a water-cooled

e-beam evaporator that was equipped with an integral flux monitor, enabling real-time control of the deposition rate. The thickness of the CeO<sub>2-x</sub>(111) films is about 3–4 nm, which is similar to that of fully oxidized CeO<sub>2</sub> film reported previously [8]. One equivalent layer (ML) is defined as  $7.89 \times 10^{14}$  CeO<sub>2</sub> units per cm<sup>2</sup> with the thickness of 0.31 nm [9]. After film growth, LEED patterns were always checked to assess the long-range order of the films. CeO<sub>2-x</sub> film exhibits a p(1.4 $\times$ 1.4) LEED pattern which are comparable to that from the fully oxidized film [17].

Ag was deposited onto the ceria films by evaporating Ag metal (99.999%, Alfa Aesar) from a tantalum basket, which was thoroughly degassed prior to use. A very slow deposition rate of Ag (0.002 ML/min) was used in our experiments. One monolayer (ML) of Ag is defined throughout as the number of Ag atoms per area in a closed-packed (111) layer of Ag atoms with lattice parameters of bulk Ag (1 ML= $1.4 \times 10^{15}$  atoms/cm<sup>2</sup>), which is about twice as much as the number of oxygen atoms in CeO<sub>2</sub>(111) exposed to the vacuum per unit area [9].

## III. RESULTS AND DISCUSSION

### A. Growth of Ag on reduced CeO<sub>2-x</sub>(111) at room temperature

It has been demonstrated that the growth mode of Ag can be affected by the roughness of the CeO<sub>2</sub> films and Ag preferentially populates the defect sites of the surface [8]. The growth of Ag is now studied on the reduced CeO<sub>2-x</sub>(111) films with different reduction degrees to further examine the effect of oxygen vacancies on the growth mode of Ag using XPS. The percentage of Ce<sup>3+</sup> concentration in the CeO<sub>2-x</sub> films was determined from the Ce3d XPS spectra, as described previously [8]. For example, when the partly reduced ceria film contains 30%Ce<sup>3+</sup>, the film is designed to be CeO<sub>1.85</sub>. While on the fully reduced CeO<sub>1.5</sub> film, only the features associated with Ce<sup>3+</sup> can be observed [16, 18]. With increasing the reduction degree of ceria, the increase in the surface roughness as well as the number of surface defects have been observed in the previous STM studies [16, 19].

As seen in Fig.1, on the CeO<sub>2</sub>(111) surface the Ag signal exhibits behavior indicative of 3D island growth with an island density of  $\sim 10^{12}$  islands/cm<sup>2</sup>, agreeing well with previous photoemission studies [8]. On the two reduced CeO<sub>2-x</sub>(111) surfaces (CeO<sub>1.85</sub> and CeO<sub>1.5</sub>), the Ag signals also indicate that the growth of Ag exhibits 3D behavior. However, the best fit for the Ag signals grown on CeO<sub>1.85</sub>(111) surface is obtained with a larger particle density of  $\sim 2 \times 10^{12}$  islands/cm<sup>2</sup> in comparison with that on the well-ordered CeO<sub>2</sub>(111) surface which was postannealed at the same temperature (980 K) as those on the reduced surfaces. Further increasing the reduction degree to CeO<sub>1.5</sub>(111) leads

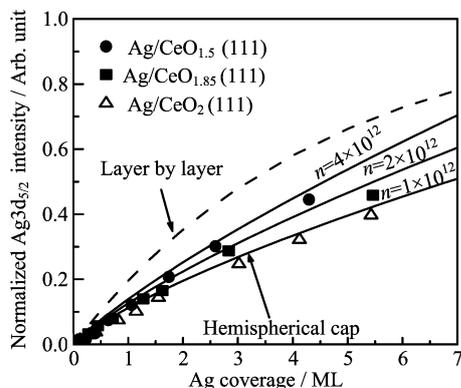


FIG. 1 Integrated  $\text{Ag}3d_{5/2}$  XPS peak intensities normalized to that of bulk Ag versus coverage for Ag growth on 4 nm thick  $\text{CeO}_{2-x}$ (111) films grown on Ru(0001) at room temperature. The solid data points represent the results from the  $\text{CeO}_{1.85}$ (111) and  $\text{CeO}_{1.5}$ (111) films, respectively, while the open data points are the results obtained from the  $\text{CeO}_2$ (111) film. The dashed curves correspond to what is expected if Ag grows in a layer-by-layer growth mode, and the solid curves represent a hemispherical cap model with constant island densities of  $4 \times 10^{12}$  and  $1 \times 10^{12}$  islands/ $\text{cm}^2$ . The inelastic mean free path used for calculation is 1.54 nm for Ag, obtained from Ref.[21], and the detection angle was  $45^\circ$ .

to a continued increase of the Ag particles density to  $\sim 4 \times 10^{12}$  islands/ $\text{cm}^2$ . This means that at the same Ag coverage, smaller Ag particles with larger island density are formed on the reduced  $\text{CeO}_{2-x}$ (111) surface as compared to those on the  $\text{CeO}_2$ (111) surface. Moreover, the more reduced the ceria film, the smaller Ag particles on it. The increased Ag particle density on the reduced ceria can be attributed to the increase of surface oxygen vacancy defect sites which have stronger bonding to Ag [10, 20]. These results agree very well with the STM studies for Ag on the  $\text{CeO}_{2-x}$  surface [10]. However, based on AES and ISS measurements, a larger Ag particle density of  $\sim 4 \times 10^{12}$  islands/ $\text{cm}^2$  on the reduced  $\text{CeO}_{1.8}$ (111)/Pt(111) surface was reported previously [9]. This discrepancy may be due to the difference in the surface structure of  $\text{CeO}_{2-x}$  film, which arises from the difference in the preparation recipe of ceria films and the substrate.

## B. Interfacial electronic properties

Reduction of  $\text{CeO}_2$ (111) upon Ag deposition was observed previously using photoelectron spectroscopy [8, 10]. As a possible origin of this phenomenon, we proposed reduction of ceria caused by the reverse spillover of lattice oxygen to the surface of the supported Ag nanoparticles [8]. We used the Auger parameter method which was first introduced by Wagner [22, 23] to distinguish the initial and final state contributions to the particle size-dependent  $\text{Ag}3d$  core level shifts. In general,

the initial state effects can be attributed to the electron charge transfer between the supported metal and the substrate and/or intrinsic size effects due to the reduced metal-metal coordination in the metal particles, while the final state effects arise from the final state screening, *i.e.*, relaxation effects, which depend on the shape and size of the particles as well as the supports [24–26]. Our experimental results suggested that the initial state contribution to the  $\text{Ag}3d$  core level shifts is negligible, and the observed positive shift is entirely due to the final state screening. Therefore, the Ag nanoparticles on  $\text{CeO}_2$ (111) remain metallic state. However, it should be mentioned that this finding disagrees with the theoretical study by Luches *et al.* [10], where a direct electron transfer from the Ag nanoparticles to the ceria support was claimed. The interactions between Ag nanoparticles and the reduced ceria surface are further studied to examine the effect of oxygen vacancies of ceria on the electronic properties of Ag. Here we also use the Auger parameter method to distinguish the relative contributions of the initial and final state effects on the Ag core-level binding energy shifts as a function of particle sizes. According to this method, the change of the Auger parameter ( $\alpha$ ), which is defined as sum of the kinetic energy (KE) of the Auger peak and the binding energy of the core level peak, approximately equals twice the final state contributions to the core level shifts [22, 23, 27].

In Fig.2 (a) and (b), the  $\text{Ag}3d_{5/2}$  core level binding energy and  $\text{Ag} M_5V_5V$  Auger transition kinetic energy of Ag growth on a  $\text{CeO}_{1.85}$ (111) film are plotted as a function of Ag coverage at 300 K. As can be seen, with decreasing Ag coverage, the  $\text{Ag}3d_{5/2}$  BE shifts to a higher BE, while the KE of the  $M_5V_5V$  Auger transition shifts to a lower KE. At 0.04 ML Ag coverage, with respect to the bulk Ag value, the  $\text{Ag}3d$  BE is higher by 0.6 eV and the  $M_5V_5V$  Auger peak position is lower by 1.5 eV. Above 10.0 ML Ag coverage, they all approach the bulk Ag value. The BE shifts of Ag with increasing Ag coverage on  $\text{CeO}_{1.85}$ (111) are similar to that on  $\text{CeO}_2$ (111) [8].

The Auger parameter  $\alpha$ , calculated from the sum of the  $\text{Ag}3d_{5/2}$  BE (Fig.2(a)) and the  $M_5V_5V$  Auger transition KE (Fig.2(b)), as a function of Ag coverage is plotted in Fig.2(c). As seen,  $\alpha$  increases with the increasing Ag coverage from 718.9 eV at 0.04 ML to 720.0 eV for the bulk value. The contributions from the final state ( $\Delta R$ ) and the initial state ( $\Delta \epsilon$ ) to the core level BE shifts estimated from the value of  $\Delta \alpha$ , as described in detail previously [8], are plotted as a function of Ag coverage in Fig.2(d). It is obvious that over the entire coverage we investigated, the final state contribution to the  $\text{Ag}3d$  core level binding energy shifts is dominant. At very low coverage (0.04 ML), the final state effects contribution is calculated to be  $\sim 0.5$  eV, while the initial state contribution is  $-0.1$  eV. Essentially initial state contribution is very small (within  $\pm 0.1$  eV) from very low (0.04 ML) to high (10.0 ML) Ag coverages. These

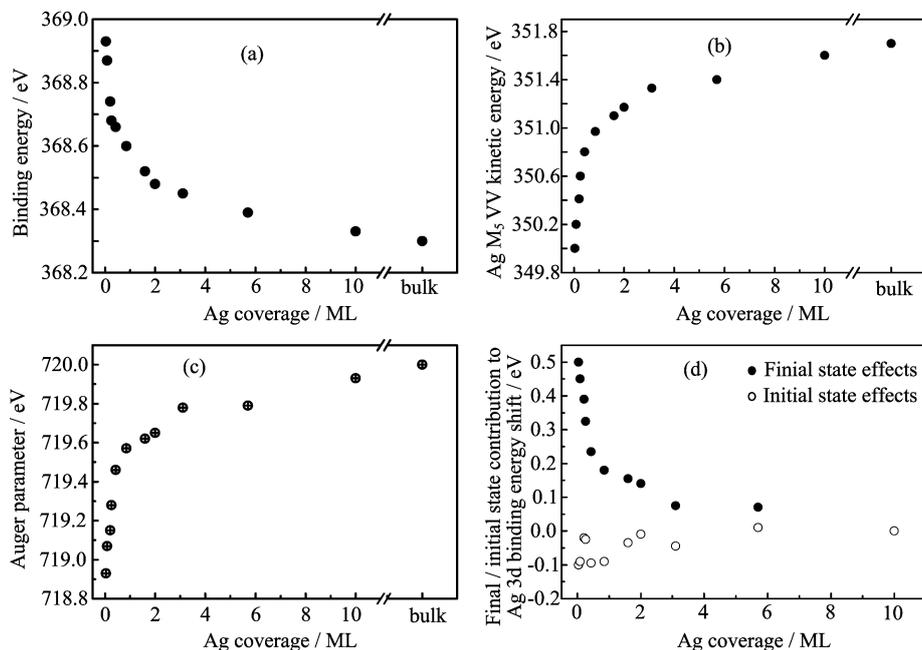


FIG. 2 (a) Ag3d<sub>5/2</sub> core level binding energy, (b) Ag M<sub>5</sub>VV Auger peak kinetic energy, (c) Auger parameter, and (d) initial state and final state contributions to the core level binding energy shifts as a function of Ag coverage on CeO<sub>1.85</sub>(111) at 300 K. The total core level shifts come from  $\Delta\varepsilon - \Delta R$ , where  $\Delta\varepsilon$  and  $\Delta R$  represent the initial state and final state contributions, respectively.

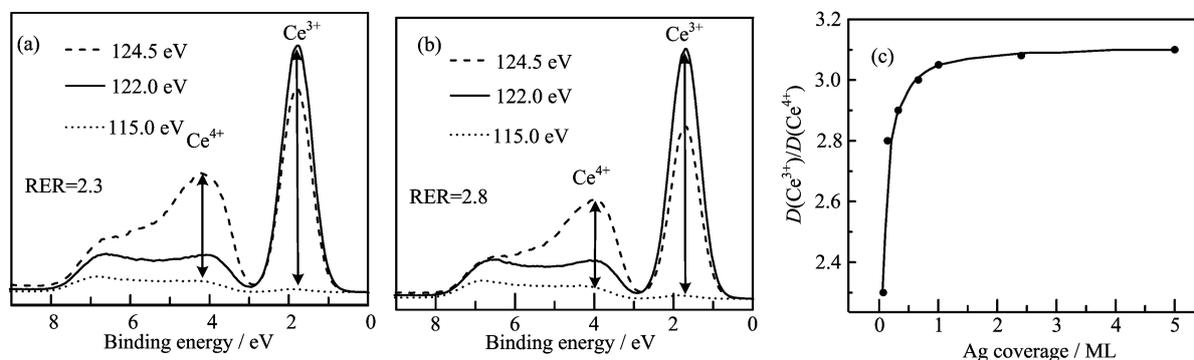


FIG. 3 Valence band photoemission spectra of (a) 4 nm clean CeO<sub>1.85</sub>(111), and (b) 0.07 ML Ag on CeO<sub>1.85</sub>(111) taken at photon energies:  $h\nu=115.0$  eV (off-resonance),  $h\nu=122.0$  eV (Ce<sup>3+</sup> resonance),  $h\nu=124.5$  eV (Ce<sup>4+</sup> resonance). (c) Resonance enhancement ratio  $D(\text{Ce}^{3+})/D(\text{Ce}^{4+})$  from RPES as a function of Ag coverage on the CeO<sub>1.85</sub>(111) film.

results indicate a relative weak interaction between Ag clusters and the reduced ceria thin film. However, since at the same coverage the 3D growth of Ag nanoparticles with larger number of island densities on the reduced ceria films compared to that on the fully oxidized ceria film suggests that the interaction of Ag with reduce ceria, in spite of the weakness, is still slightly stronger than Ag with fully oxidized ceria [8]. This is further confirmed by the higher sintering temperatures of the Ag nanoparticles on reduced ceria at a given coverage.

Changes of the oxidation state of Ce upon Ag deposition can be monitored by valence band spectra following the characteristic Ce4f photoemission feature of Ce<sup>3+</sup> [8]. Thus, a primary indication of CeO<sub>2</sub> reduction due

to Ag deposition at 300 K was observed [8]. However, in the present work, the intensity of the Ce4f peak in VB spectra is already very strong for the clean partially reduced CeO<sub>2-x</sub> films. It is difficult to identify small changes in the Ce4f intensity corresponding to changes of the Ce<sup>3+</sup> concentration caused by Ag deposition. Moreover, the Ag deposition even causes the damping of the Ce4f signals. Resonant photoelectron spectroscopy (RPES) has been proven to be more sensitive to the stoichiometry variations than the analysis of VB spectra and is not dependent on the absolute ceria amount and/or spectra overlapping with other peaks belonging to additive or substrates if present [11]. The RPES showed a strong dependence on the valence state with

on-resonance spectra obtained near 125.0 and 122.0 eV for  $4f^0$  and  $4f^1$  configurations in the ground state, respectively [12]. According to the previously published results [11, 28], we can recognize two resonant features located at BEs of 4.0 and 1.6 eV that reach their maximum enhancements at  $h\nu=124.5$  eV ( $\text{Ce}^{4+}$  resonance) and 122.0 eV ( $\text{Ce}^{3+}$  resonance), respectively. At the photon energy of 115.0 eV, there is no resonance for both  $\text{Ce}^{4+}$  and  $\text{Ce}^{3+}$ . The RPE spectra of the clean  $\text{CeO}_{1.85}$ (111) surface at photon energies of 115.0, 122.0, and 124.5 eV are shown in Fig.3(a). In Fig.3(b) the corresponding resonant spectra of 0.07 ML Ag deposited  $\text{CeO}_{1.85}$ (111) are shown for comparison. The resonance enhancement ratio (RER),  $D(\text{Ce}^{3+})/D(\text{Ce}^{4+})$ , can be calculated by dividing the two resonant maxima after subtraction of the off-resonance spectrum. For the clean  $\text{CeO}_{1.85}$  film, the ratio  $D(\text{Ce}^{3+})/D(\text{Ce}^{4+})$  is 2.3. Upon 0.07 ML Ag deposition, this ratio increases to 2.8. Moreover, with increasing Ag coverage, the RER further increases. As shown in Fig.3(c), the RER ratio increases rapidly at coverage up to 1 ML followed by a slower increase; it reaches the value of 3.1 at 5 ML Ag coverage. Therefore, it is clear that the  $\text{CeO}_{1.85}$ (111) surface is further reduced after Ag deposition. This finding is similar to that of Ag on stoichiometric  $\text{CeO}_2$ (111) [8, 10]. Since the above Auger parameter analysis shows that a very weak interaction between Ag nanoparticles and the reduced ceria thin film, the reduction of  $\text{CeO}_{2-x}$  resulting electron transfer from Ag to  $\text{CeO}_{2-x}$ (111) can be excluded. As suggested previously [8], the increase in the  $\text{Ce}^{3+}$  concentration after Ag deposition may also be ascribed to the reverse spillover of oxygen from ceria to the Ag particles.

### C. Thermal sintering

It has been reported previously that annealing the Ag nanoparticles on fully oxidized  $\text{CeO}_2$ (111) in UHV leads to significant sintering of Ag particles before they desorb from the surface [8]. To determine the thermal stability of Ag nanoparticles on reduced  $\text{CeO}_{2-x}$ , we have carried out the following experiments: Ag deposited on  $\text{CeO}_{1.85}$ (111) at 300 K with two different coverages were annealed at elevated temperatures, after which Ag3d spectra were collected at 300 K. As shown in Fig.4(a), the Ag3d<sub>5/2</sub> peak intensities normalized to the value at 300 K are plotted as a function of temperature for 0.1 and 1.0 ML Ag on  $\text{CeO}_{1.85}$ (111), respectively. With increasing annealing temperature, the Ag3d<sub>5/2</sub> intensity for 0.1 ML Ag starts to decrease already at 600 K, while for 1.0 ML Ag the Ag3d<sub>5/2</sub> intensity remains nearly unchanged up to 700 K. When the temperature is higher than 700 K, the Ag3d<sub>5/2</sub> intensities from both surfaces decrease rapidly. At about 900 K, almost no Ag signal can be detected. According to previous studies [8], the decrease in intensity of Ag3d<sub>5/2</sub> spectra during annealing before 800 K can be attributed to particle sintering

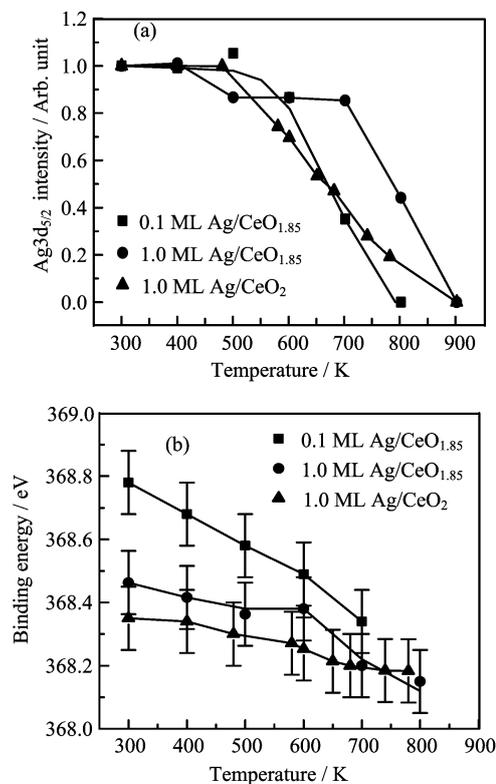


FIG. 4 (a) Ag3d<sub>5/2</sub> peak intensities for 0.1 and 1.0 ML Ag on  $\text{CeO}_{1.85}$ (111), and 1.0 ML Ag on  $\text{CeO}_2$ (111) as a function of annealing temperature. (b) Binding energies of Ag3d<sub>5/2</sub> spectra for 0.1 and 1.0 ML Ag on  $\text{CeO}_{1.85}$ (111), and 1.0 ML Ag on  $\text{CeO}_2$ (111) as a function of annealing temperature. The spectra were collected at 300 K.

on the surface. Above 800 K, the sharp decrease in peak intensity is due to the Ag desorption from the surface. By 900 K, all Ag desorbs from the surface, leading to no detectable Ag signal by XPS. The sintering temperature for Ag on the reduced ceria films is found a little higher ( $\sim 100$  K) than the case of the same coverage of Ag on the oxidized films. This is attributed to the oxygen vacancies on the reduced  $\text{CeO}_{2-x}$  surface which can stabilize the Ag particles through a stronger interaction between oxygen vacancies and Ag particles [9, 10, 29]. The initial sintering temperature for a low coverage Ag film (0.1 ML) is lower than that for a high coverage film (1.0 ML), indicating that larger Ag particles are more thermally stable than the smaller ones on the reduced ceria. This phenomenon is similar to what was observed for Ag on stoichiometric  $\text{CeO}_2$ (111) [8] and Au on  $\text{ZrO}_2$ (111) [30] which may be attributed to that the small Ag particles undergo sintering not only by the Ostwald ripening but also by facile diffusion on the surface and coalesce, whereas the large particles might sinter mainly through the Ostwald ripening [31]. In addition, the desorption temperature of small Ag particles is lower than that of large particles. These results are similar to those of Ag on  $\text{CeO}_2$ (111) where STM showed

that the smaller Ag particles desorb more easily on the surface [10].

The Ag sintering process on CeO<sub>1.85</sub>(111) before desorption is further confirmed by the observation of the shifts of Ag3d<sub>5/2</sub> BEs as well as the changes of the full width of half-maximum (FWHM) of the Ag3d<sub>5/2</sub> peaks. Figure 4(b) displays the variations of Ag3d<sub>5/2</sub> BEs as a function of annealing temperature for 0.1 and 1.0 ML Ag on CeO<sub>1.85</sub>(111), respectively. Similar to the observations of Ag on CeO<sub>2</sub>(111) [8] for both Ag coverages, the BE of the Ag3d<sub>5/2</sub> peak shifts toward lower BE, and the FWHM (not shown) of the Ag3d<sub>5/2</sub> peak decreases during annealing. The changes of both BE and FWHM of Ag3d<sub>5/2</sub> peaks with temperature are more apparent for 0.1 ML Ag than for 1.0 ML since the initial particle size is smaller in the former case. As discussed in our previous work [8], they can be attributed to the sintering process of Ag on the CeO<sub>1.85</sub>(111) surface.

#### IV. CONCLUSION

We used RPES and XPS to investigate the growth, nucleation, and electronic properties of Ag on the reduced ceria thin films grown on Ru(0001). The results clearly indicate that Ag grows three-dimensionally on the CeO<sub>2-x</sub>(111) surface at 300 K. The reduced CeO<sub>2-x</sub> surface has a higher defects density, which causes the formation of Ag nanoparticles with smaller particles and a higher particle density compared to those on CeO<sub>2</sub>. Final state effects are concluded to be primarily responsible for the core level binding energy shifts of Ag deposited on CeO<sub>1.85</sub>(111) surface. No strong interfacial interaction between Ag and ceria is found. Nevertheless, some more Ce<sup>3+</sup> states appear on the reduced ceria surface after Ag deposition. The oxygen vacancies can stabilize the adsorbed Ag nanoparticles, leading to a slightly higher sintering temperature of Ag nanoparticles on the reduced CeO<sub>2-x</sub>(111) surfaces.

#### V. ACKNOWLEDGMENTS

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- [1] P. Bera, K. C. Patil, and M. S. Hegde, *Phys. Chem. Chem. Phys.* **2**, 3715 (2000).
- [2] S. Chang, M. Li, Q. Hua, L. Zhang, Y. Ma, B. Ye, and W. Huang, *J. Catal.* **293**, 195 (2012).
- [3] L. Kundakovic and M. Flytzani-Stephanopoulos, *J. Catal.* **179**, 203 (1998).
- [4] S. Imamura, D. Uchihori, K. Utani, and T. Ito, *Catal. Lett.* **24**, 377 (1994).
- [5] E. Aneggi, J. Llorca, C. de Leitenburg, G. Dolcetti, and A. Trovarelli, *Appl. Catal. B* **91**, 489 (2009).
- [6] L. L. Murrell and R. T. Carlin, *J. Catal.* **159**, 479 (1996).
- [7] K. Shimizu, H. Kawachi, and A. Satsuma, *Appl. Catal. B* **96**, 169 (2010).
- [8] D. D. Kong, G. D. Wang, Y. H. Pan, S. W. Hu, J. B. Hou, H. B. Pan, C. T. Campbell, and J. F. Zhu, *J. Phys. Chem. C* **115**, 6715 (2011).
- [9] J. A. Farmer, J. H. Baricuatro, and C. T. Campbell, *J. Phys. Chem. C* **114**, 17166 (2010).
- [10] P. Luches, F. Pagliuca, S. Valeri, F. Illas, G. Preda, and G. Pacchioni, *J. Phys. Chem. C* **116**, 1122 (2012).
- [11] M. Skoda, M. Cabala, I. Matolinova, K. C. Prince, T. Skala, F. Sutara, K. Veltruska, and V. Matolin, *J. Chem. Phys.* **130**, 7 (2009).
- [12] M. Matsumoto, K. Soda, K. Ichikawa, S. Tanaka, Y. Taguchi, K. Jouda, O. Aita, Y. Tezuka, and S. Shin, *Phys. Rev. B* **50**, 11340 (1994).
- [13] S. Hufner, *J. Phys. F* **16**, L31 (1986).
- [14] D. R. Mullins, P. V. Radulovic, and S. H. Overbury, *Surf. Sci.* **429**, 186 (1999).
- [15] J. L. Lu, H. J. Gao, S. Shaikhutdinov, and H. J. Freund, *Surf. Sci.* **600**, 5004 (2006).
- [16] Y. H. Zhou, J. M. Perket, and J. Zhou, *J. Phys. Chem. C* **114**, 11853 (2010).
- [17] W. D. Xiao, Q. L. Guo, and E. G. Wang, *Chem. Phys. Lett.* **368**, 527 (2003).
- [18] D. R. Mullins, S. H. Overbury, and D. R. Huntley, *Surf. Sci.* **409**, 307 (1998).
- [19] J. L. Lu, H. J. Gao, S. Shaikhutdinov, and H. J. Freund, *Catal. Lett.* **114**, 8 (2007).
- [20] M. Baron, O. Bondarchuk, D. Stacchiola, S. Shaikhutdinov, and H. J. Freund, *J. Phys. Chem. C* **113**, 6042 (2009).
- [21] S. Tanuma, C. J. Powell, and D. R. Penn, *Surf. Interface Anal.* **17**, 911 (1991).
- [22] C. D. Wagner, *Anal. Chem.* **44**, 967 (1972).
- [23] C. D. Wagner, *Anal. Chem.* **47**, 1201 (1975).
- [24] M. G. Mason, *Phys. Rev. B* **27**, 748 (1983).
- [25] I. Lopez-Salido, D. C. Lim, R. Dietsche, N. Bertram, and Y. D. Kim, *J. Phys. Chem. B* **110**, 1128 (2006).
- [26] K. Luo, X. Lai, C. W. Yi, K. A. Davis, K. K. Gath, and D. W. Goodman, *J. Phys. Chem. B* **109**, 4064 (2005).
- [27] C. D. Wagner, L. H. Gale, and R. H. Raymond, *Anal. Chem.* **51**, 466 (1979).
- [28] V. Matolin, V. Johánek, M. Skoda, N. Tsud, K. C. Prince, T. Skala, and I. Matolinova, *Langmuir* **26**, 13333 (2010).
- [29] J. A. Farmer and C. T. Campbell, *Science* **329**, 933 (2010).
- [30] Y. H. Pan, Y. Gao, G. D. Wang, D. D. Kong, L. Zhang, J. B. Hou, S. W. Hu, H. B. Pan, and J. F. Zhu, *J. Phys. Chem. C* **115**, 10744 (2011).
- [31] X. Yu, L. S. Xu, W. H. Zhang, Z. Q. Jiang, J. F. Zhu, and W. X. Huang, *Chin. J. Chem. Phys.* **22**, 339 (2009).